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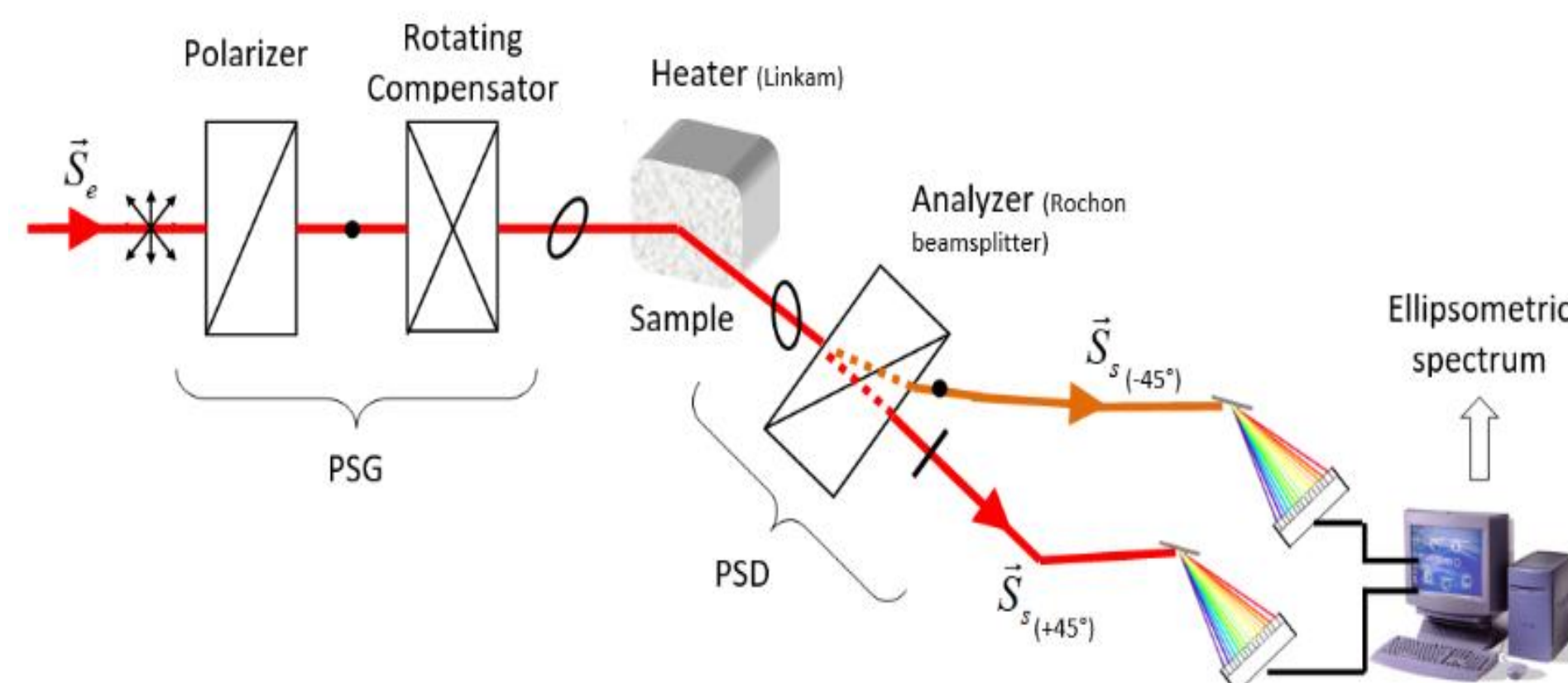
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Context

- Silver nanoparticles thermal growth in PVA thin films.
- Realtime monitoring by spectroscopic ellipsometry in the visible spectral range.
- Ellipsometric spectra analysis with the Shape Distributed Effective Medium Theory.
- Films' optical properties determination.
- Growth kinetics interpreted from volume fraction time evolution.

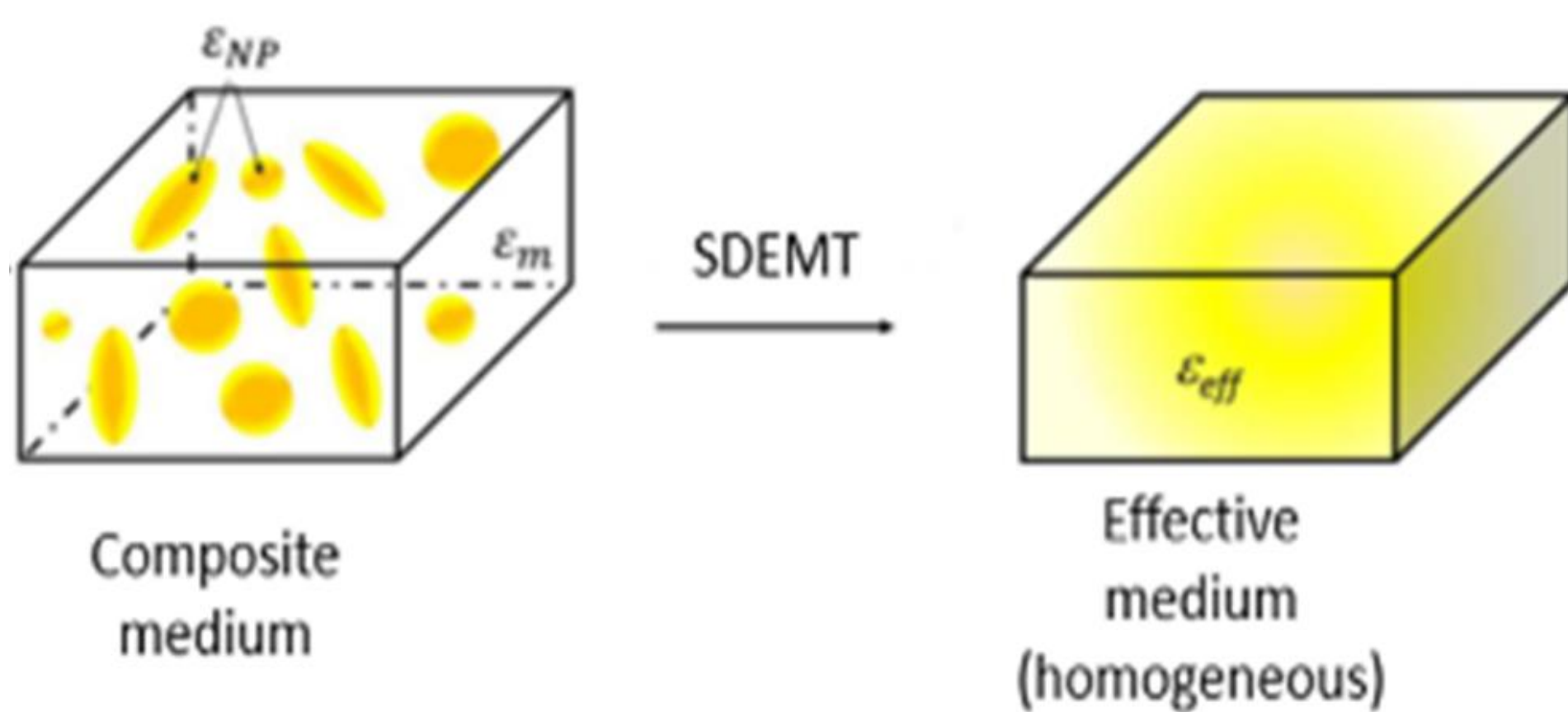
Materials and methods

- Spin-coating at 5000 rpm of AgNO₃-PVA aqueous solutions.
- Realtime Rotating Compensator Spectroscopic Ellipsometry.
- Transmission Electron Microscopy



Model

Shape Distributed Effective Medium Theory



$$\epsilon_{eff} = \frac{(1-f)\epsilon_m + f\epsilon_{NP} < \beta >}{(1-f) + f < \beta >}$$

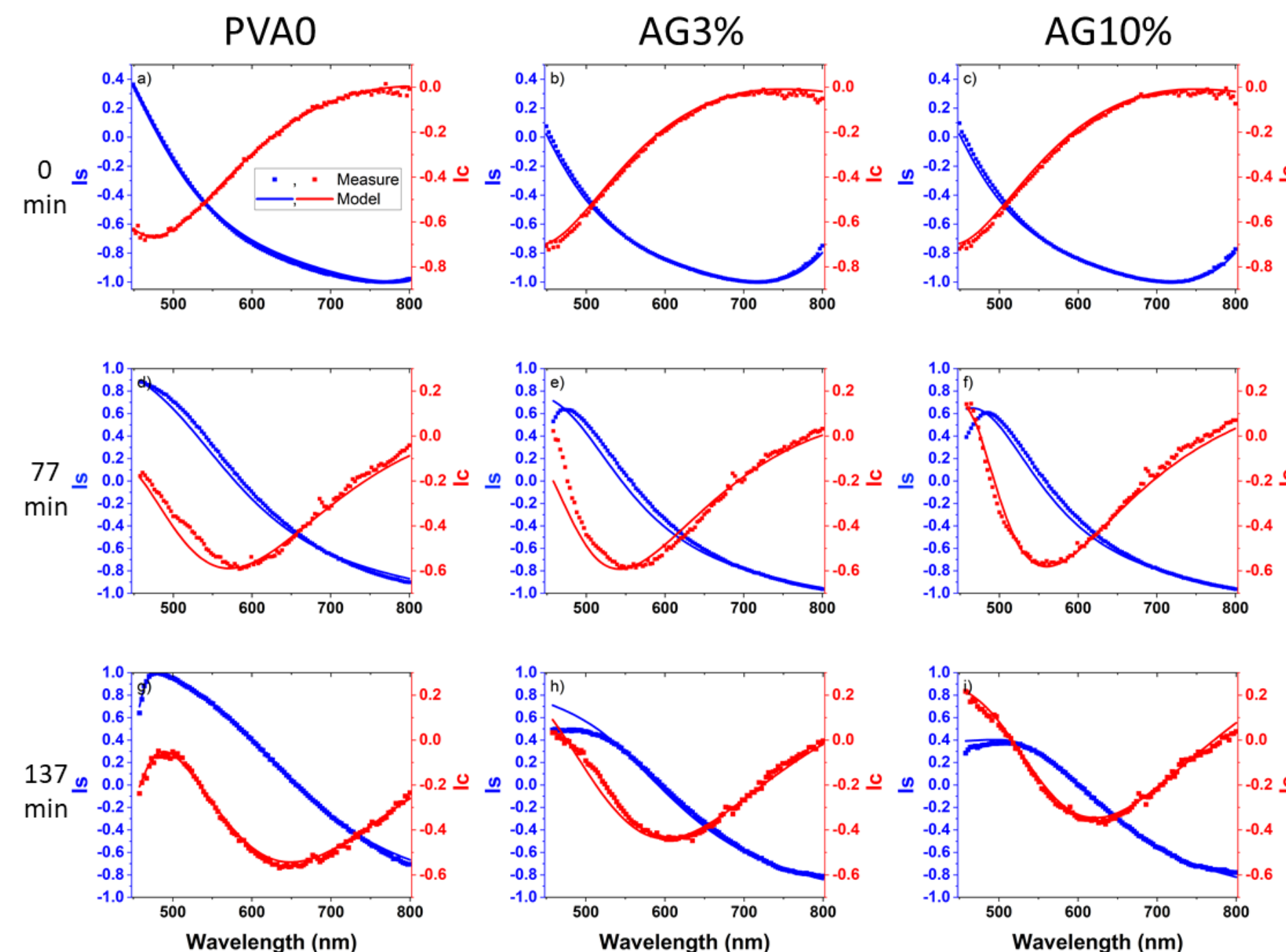
$$\beta(L_1, L_2) = \frac{1}{3} \sum_{i=1}^3 \frac{\epsilon_m}{\epsilon_m + L_i(\epsilon_{NP} - \epsilon_m)}$$

$$L_i = \frac{r_2 r_3}{2} \int_0^{+\infty} \frac{dq}{(q + r_i^2) \sqrt{\prod_{i=1}^3 (q + r_i^2)}}$$

SDEMT takes into account the shape distribution of NPs inside the dielectric matrix and the depolarization parameters are related to the three aspect ratios of the NPs considered ellipsoids with three main axes.

Results

Ellipsometric spectra

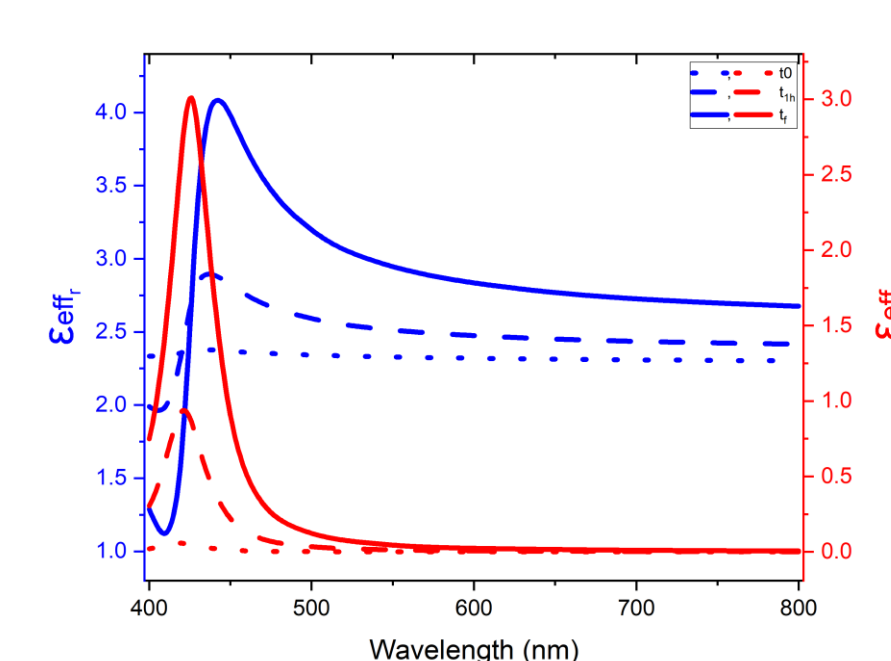
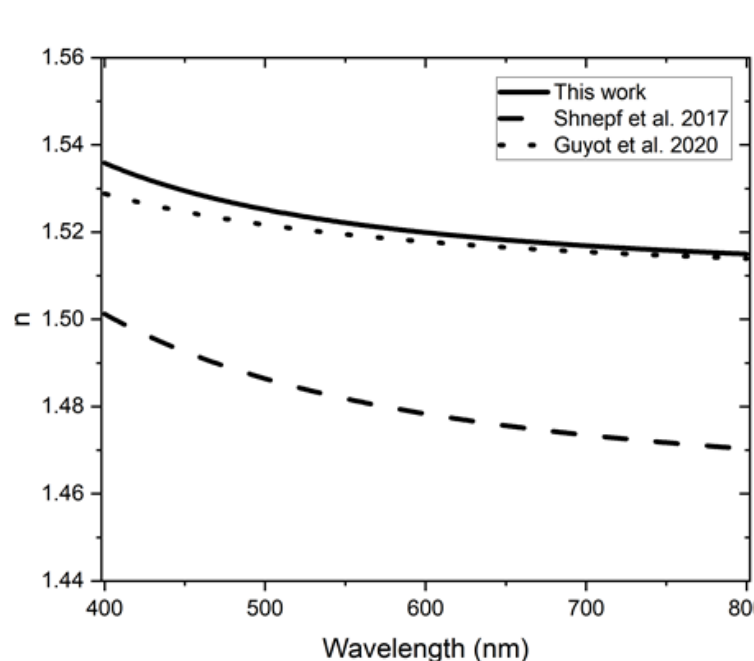


≠ Spectra → ≠ Optical pr.
Model ~ Measure

Optical Properties

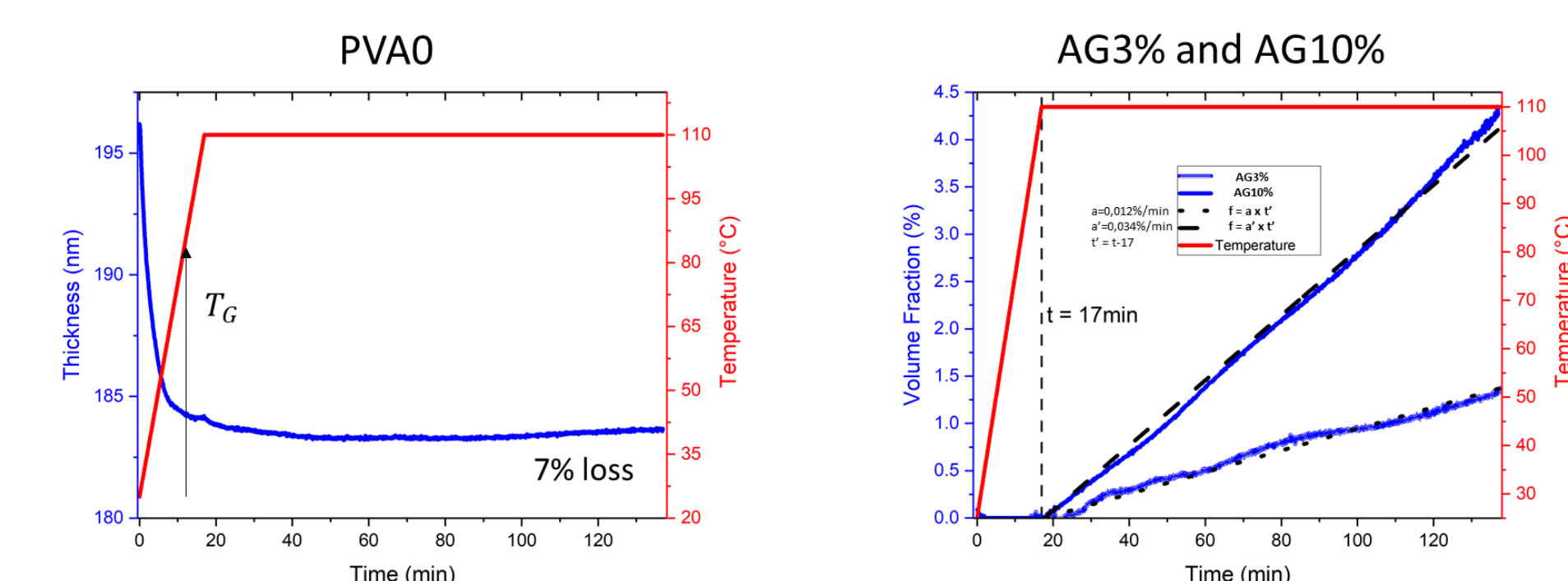
PVA0 n, k=0

AG10%



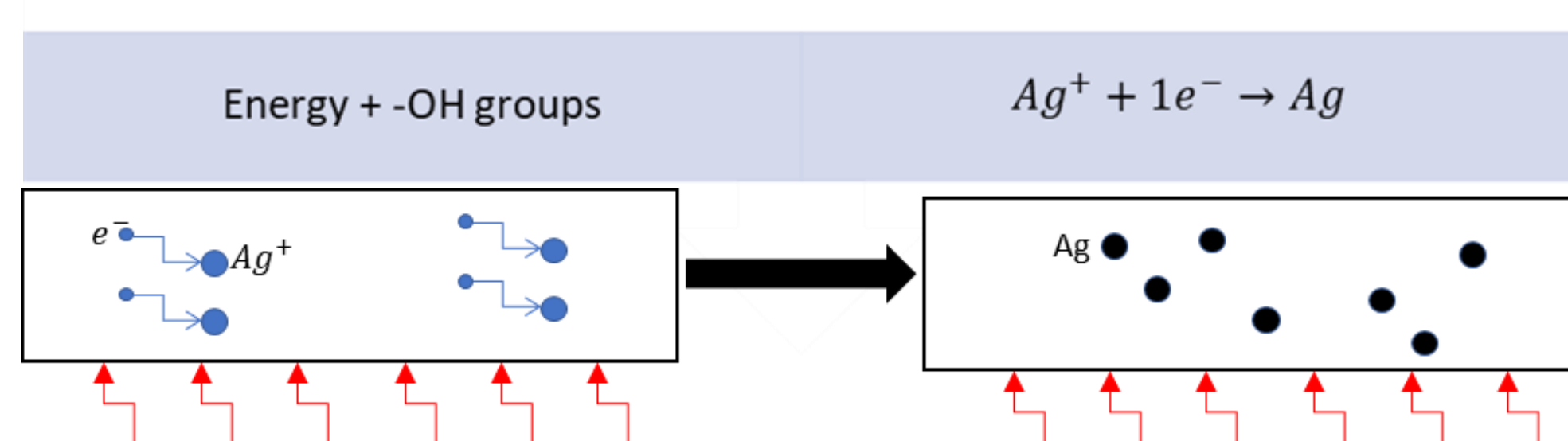
- Evolution of the dielectric function: Kramers-Kronig equations ✓
- 422nm < λ_{res} < 426nm : Fröhlich's condition – Spherical AgNPs

Thickness and volume fraction time evolution

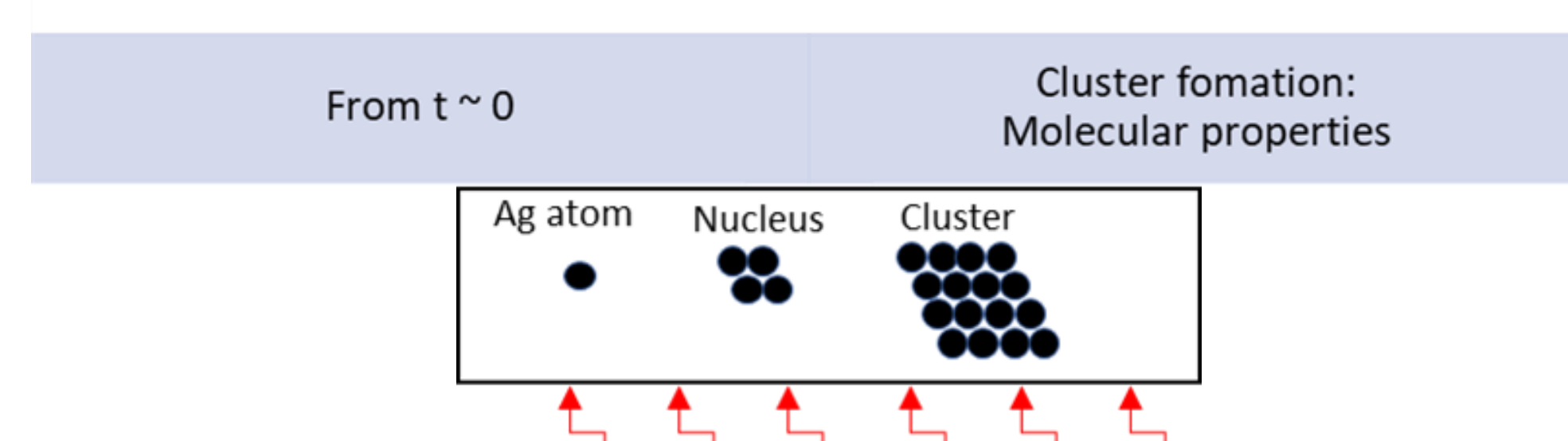


- Film shrinking during annealing due to excessive solvent evaporation
- Growth detection begins at 17 min
- Slow Zero order kinetic time evolution of volume fraction → Diffusion limited Growth mechanism

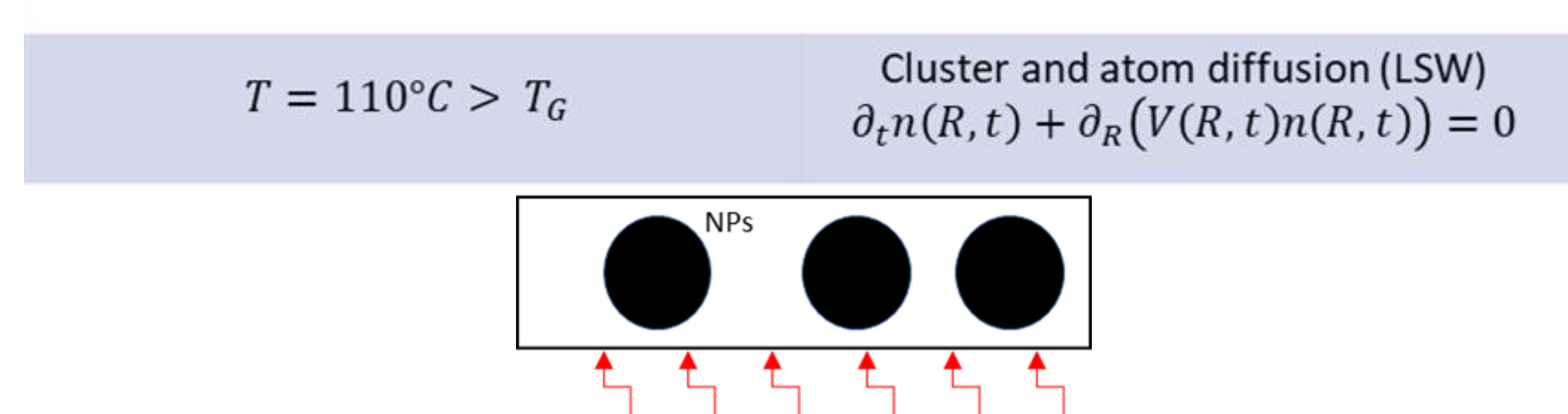
Reduction



Nucleation and aggregation

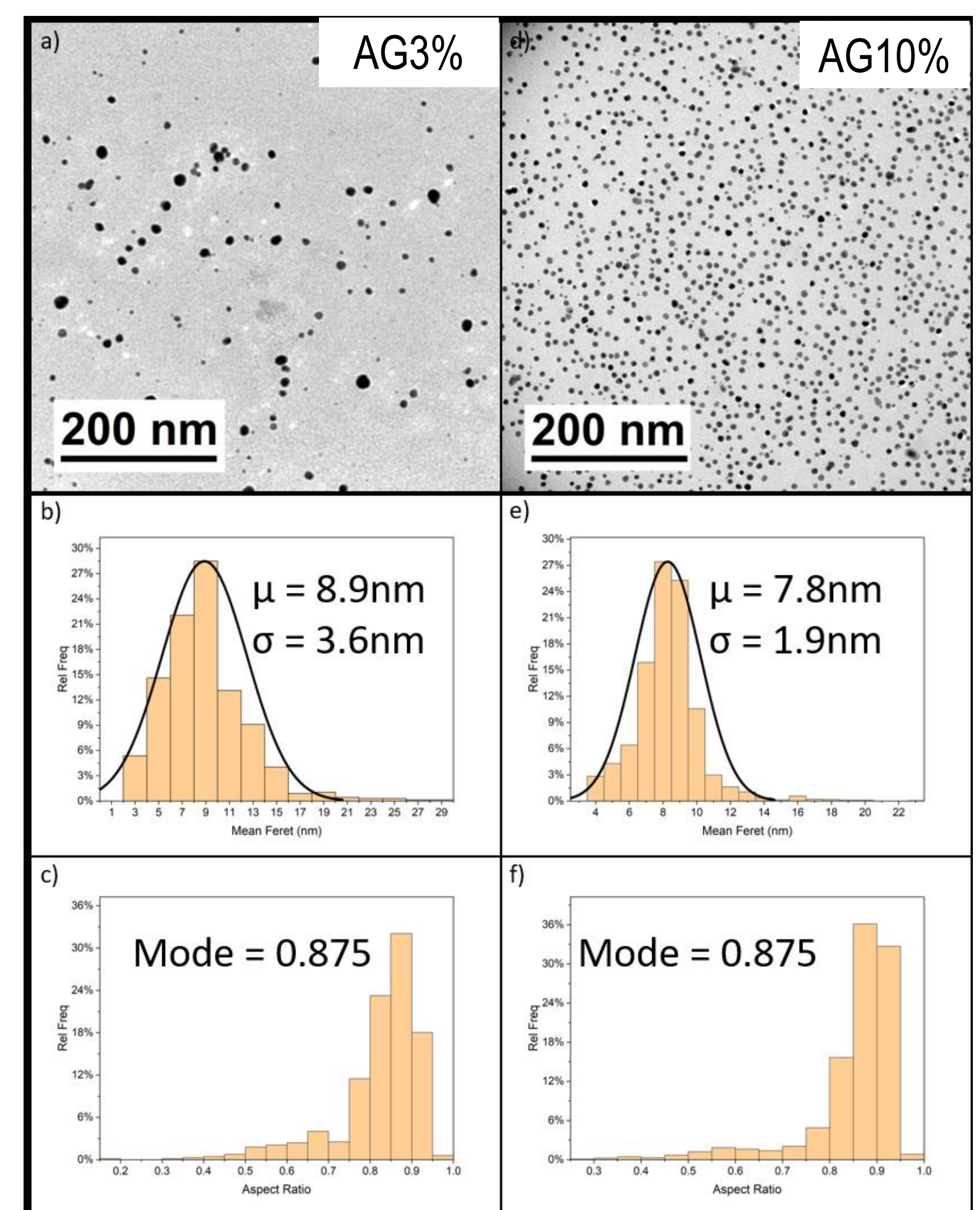


Ostwald's ripening

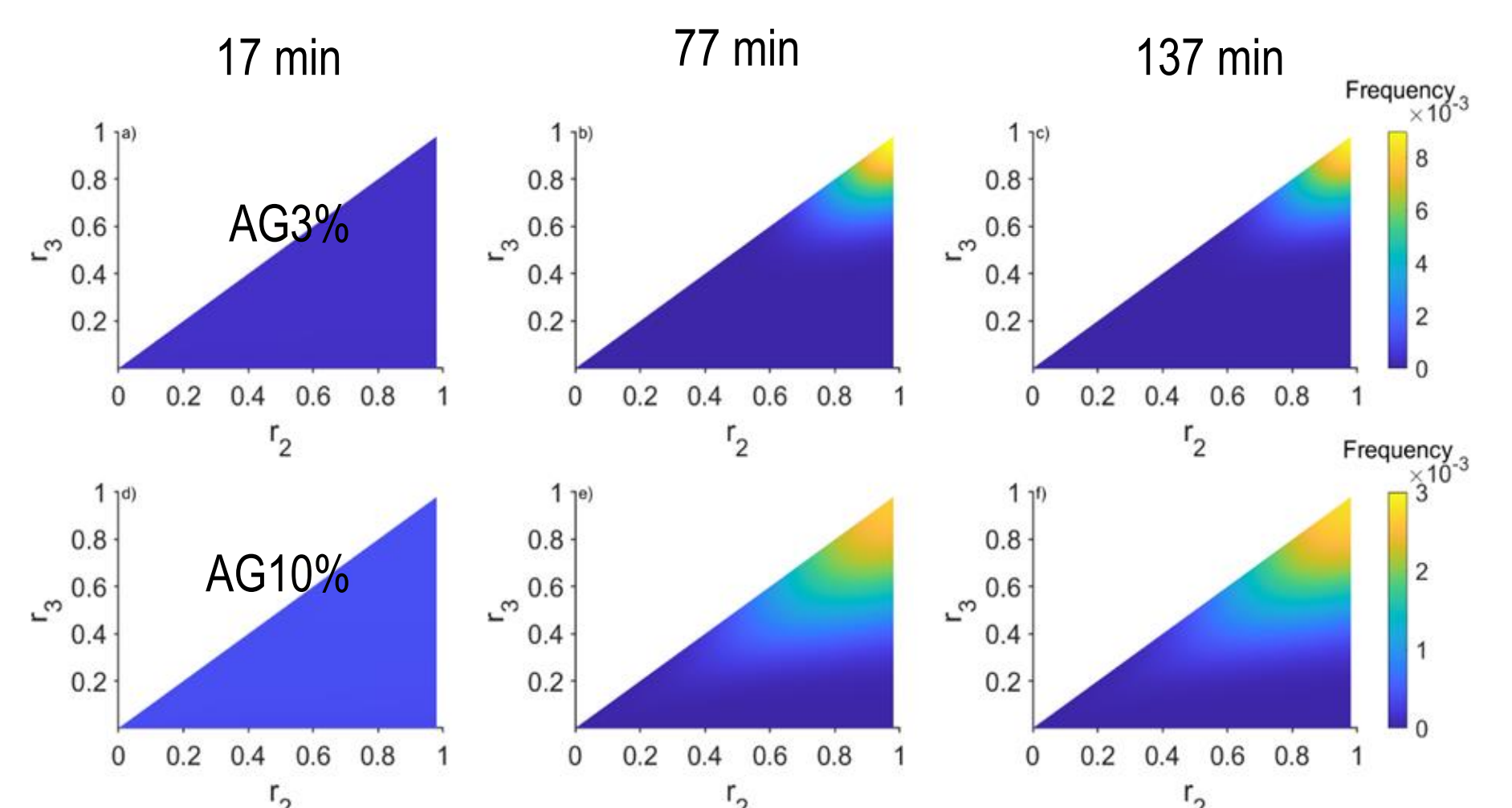


Results

TEM imaging



Aspect ratio distribution based on SE results and SDEMT calculations



Spherical centered distributions

Conclusion

- Silver NPs growth in PVA matrix by thermal annealing
- Optical in situ monitoring by SE
- SDEMT modeling:
 - Thickness: loss during annealing
 - Volume fraction time evolution: Zero order kinetic
 - Growth mechanism: governed by Ostwald's ripening
 - Shape distribution: Spherical centered

References

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